g GE Energy	**Functional Testing Specification**
Parts & Repair Services ***Louisville, KY***	**LOU-GED-IS200DSCBH1A**

Test Procedure for a IS200DSCBH1A card

DOCUMENT REVISION STATUS: Determined by the last entry in the "REV" and "DATE" column

REV.	DESCRIPTION	SIGNATURE	REV. DATE
A	Initial release	Scott Cash	9-14-2011
B			
C			

PREPARED BY	REVIEWED BY	REVIEWED BY	QUALITY APPROVAL
B. Cash			Charlie Wade
DATE	**DATE**	**DATE**	**DATE**
9/14/2011			9/14/2011

1. SCOPE

1.1 This is a functional testing procedure for aIS200DSCBH1A card.

2. STANDARDS OF QUALITY

2.1 Refer to the current revision of the IPC-A-610 standard for workmanship standards.

3. APPLICABLE DOCUMENTS

3.1 The following document(s) shall form part of this specification to the extent specified herein. Unless otherwise indicated, the latest issue shall apply.
3.1.1 Check board's electronic folder for more information

4. ENGINEERING REQUIREMENTS

4.1 Equipment Cleaning
4.1.1 Equipment should be clean and free of debris prior to applying power unless performing an initial check. Refer to site specific SRA's for cleaning guidelines.
4.2 Equipment Inspection
4.2.1 Equipment should be visually inspected for any defects prior to applying power. This inspection should include the following as a minimum:
4.2.1.1 Wires - broken, cracked, or loosely connected
4.2.1.2 Terminal strips / connectors - broken or cracked
4.2.1.3 Components - visually damaged
4.2.1.4 Capacitors - bloated or leaking
4.2.1.5 Solder joints - damaged or cold
4.2.1.6 Circuit board - burned or de-laminated
4.2.1.7 Printed wire runs / Traces - burned or damaged

5. EQUIPMENT REQUIRED

5.1 The following equipment is required to perform the process requirements. Equipment may be substituted provided that all accuracy's and test ratios are equivalent or better.

Qty	Reference #	Description
1	Fluke 87	Multi meter
1	ID Chip Test	ID chip test stand

6. Modifications/Upgrades

6.1 Check Orange Book for any modifications or upgrades.

7. Testing Process

7.1 Setup

7.1.1 Find a small piece of wire or small meter lead to fit inside a DB type connector.

7.2 Testing Procedure

7.2.1 Move jumpers JP1 thru JP6 to “Caps” then verify the following Table.

Point A	Point B	Measurement
TB1-6	TB1-48	1M Ohms +\- 5%
TB1-13	TB1-48	1M Ohms +\- 5%
TB1-20	TB1-48	1M Ohms +\- 5%
TB1-27	TB1-48	1M Ohms +\- 5%
TB1-34	TB1-48	1M Ohms +\- 5%
TB1-41	TB1-48	1M Ohms +\- 5%

7.2.2 Move jumpers JP1 thru JP6 to “SCOM” then verify the following table.

Point A	Point B	Measurement
TB1-6	TB1-48	100 Ohms +\- 5%
TB1-13	TB1-48	100 Ohms +\- 5%
TB1-20	TB1-48	100 Ohms +\- 5%
TB1-27	TB1-48	100 Ohms +\- 5%
TB1-34	TB1-48	100 Ohms +\- 5%
TB1-41	TB1-48	100 Ohms +\- 5%

7.2.3 Verify continuity per the following table.

Point A	Point B	Measurement
TB1-1	JA-1	O Ohms +\- 2 ohms
TB1-2	JA-20	O Ohms +\- 2 ohms
TB1-3	JA-2	O Ohms +\- 2 ohms
TB1-4	JA-21	O Ohms +\- 2 ohms
TB1-5	JA-3	O Ohms +\- 2 ohms
TB1-8	JA-4	O Ohms +\- 2 ohms
TB1-9	JA-23	O Ohms +\- 2 ohms
TB1-10	JA-5	O Ohms +\- 2 ohms
TB1-11	JA-24	O Ohms +\- 2 ohms
TB1-12	JA-6	O Ohms +\- 2 ohms
TB1-15	JA-7	O Ohms +\- 2 ohms
TB1-16	JA-26	O Ohms +\- 2 ohms
TB1-17	JA-8	O Ohms +\- 2 ohms
TB1-18	JA-27	O Ohms +\- 2 ohms
TB1-19	JA-9	O Ohms +\- 2 ohms
TB1-22	JA-10	O Ohms +\- 2 ohms
TB1-23	JA-29	O Ohms +\- 2 ohms
TB1-24	JA-11	O Ohms +\- 2 ohms
TB1-25	JA-30	O Ohms +\- 2 ohms
TB1-26	JA-12	O Ohms +\- 2 ohms
TB1-29	JA-13	O Ohms +\- 2 ohms
TB1-30	JA-32	O Ohms +\- 2 ohms
TB1-31	JA-14	O Ohms +\- 2 ohms
TB1-32	JA-33	O Ohms +\- 2 ohms
TB1-33	JA-15	O Ohms +\- 2 ohms
TB1-36	JA-16	O Ohms +\- 2 ohms
TB1-37	JA-35	O Ohms +\- 2 ohms
TB1-38	JA-17	O Ohms +\- 2 ohms
TB1-39	JA-36	O Ohms +\- 2 ohms
TB1-40	JA-18	O Ohms +\- 2 ohms
TB1-48	TB1-7	O Ohms +\- 2 ohms
TB1-48	TB1-14	O Ohms +\- 2 ohms
TB1-48	TB1-28	O Ohms +\- 2 ohms
TB1-48	TB1-35	O Ohms +\- 2 ohms
TB1-48	TB1-42	O Ohms +\- 2 ohms

7.2.4 Check capacitors C1 thru C8, (+/- 20%)

7.2.5 Verify ID chip.

7.3 ***TEST COMPLETE ***

8. Notes

8.1 None at this time.

9. Attachments

9.1 None at this time.